Search Notes



	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/776,347	TANAKA ET AL.	
	Examiner	Art Unit	
_	Yonel Beaulieu	3661	

SEARCHED					
Class	Subclass	Date	Examiner		
701	41	1/15/2006	YB		
	42				
180	443	1/20/2006	YB		
	444				
74	7D	1/20/2006	YB		
	10.85				
	425				
	724				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST + Inventor's Name Search	1/15/2006	YB		
WEST	1/20/2006	YB		
Consulted w/Ex. Boehler (180)	1/20/2006	YB		
		·· <u> </u>		